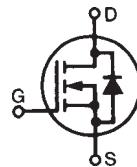


# High Voltage Power MOSFET

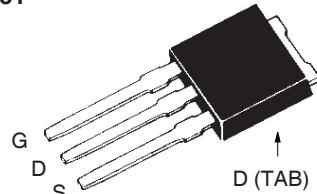
**IXTU05N100**  
**IXTY05N100**

**V<sub>DSS</sub>** = **1000V**  
**I<sub>D25</sub>** = **750mA**  
**R<sub>DS(on)</sub>** ≤ **17Ω**

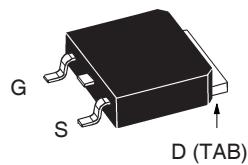
N-Channel Enhancement Mode  
Avalanche Rated



TO-251



TO-252



G = Gate      D = Drain  
S = Source      TAB = Drain

Symbol	Test Conditions	Maximum Ratings		
V <sub>DSS</sub>	T <sub>J</sub> = 25°C to 150°C	1000		V
V <sub>DGR</sub>	T <sub>J</sub> = 25°C to 150°C, R <sub>GS</sub> = 1MΩ	1000		V
V <sub>GSS</sub>	Continuous	±30		V
V <sub>GSM</sub>	Transient	±40		V
I <sub>D25</sub>	T <sub>C</sub> = 25°C	750		mA
I <sub>DM</sub>	T <sub>C</sub> = 25°C, pulse width limited by T <sub>JM</sub>	3		A
I <sub>A</sub>	T <sub>C</sub> = 25°C	1		A
E <sub>AS</sub>	T <sub>C</sub> = 25°C	100		mJ
dv/dt	I <sub>S</sub> ≤ I <sub>DM</sub> , V <sub>DD</sub> ≤ V <sub>DSS</sub> , T <sub>J</sub> = 150°C	3		V/ns
P <sub>D</sub>	T <sub>C</sub> = 25°C	40		W
T <sub>J</sub>		-55 ... +150		°C
T <sub>JM</sub>		150		°C
T <sub>stg</sub>		-55 ... +150		°C
T <sub>L</sub>	1.6mm (0.062 in.) from case for 10s	300		°C
T <sub>SOLD</sub>	Plastic body for 10s	260		°C
F <sub>c</sub>	Mounting force	1.13 / 10		Nm/lb.in.
Weight	TO-251	0.40		g
	TO-252	0.35		g

Symbol	Test Conditions (T <sub>J</sub> = 25°C, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	1000		V
V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5		V
I <sub>GSS</sub>	V <sub>GS</sub> = ± 30V, V <sub>DS</sub> = 0V			±100 nA
I <sub>DSS</sub>	V <sub>DS</sub> = V <sub>DSS</sub> V <sub>GS</sub> = 0V			25 μA
		T <sub>J</sub> = 125°C		500 μA
R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 375mA, Note 1		17	Ω

## Features

- International standard packages
- Fast switching times
- Avalanche Rated
- Rugged polysilicon gate cell structure
- Extended FBSOA

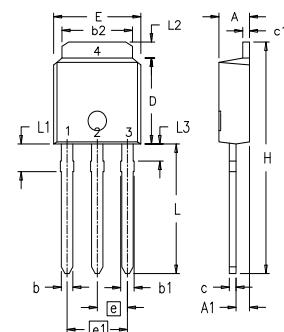
## Applications

- Switch-mode and resonant-mode power supplies
- Flyback inverters
- DC choppers

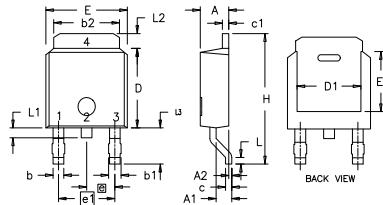
## Advantages

- High power density
- Space savings

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
$g_{fs}$	$V_{DS} = 20\text{V}$ , $I_D = 500\text{mA}$ , Note 1	0.55	0.93	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1\text{MHz}$	260	pF	
		22	pF	
		8	pF	
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	<b>Resistive Switching Times</b> $V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 1\text{A}$ $R_G = 47\Omega$ (External)	11	ns	
		19	ns	
		40	ns	
		28	ns	
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 1\text{A}$	7.8	nC	
		1.4	nC	
		4.1	nC	
$R_{thJC}$			3.1 $^\circ\text{C}/\text{W}$	
$R_{thCA}$			110 $^\circ\text{C}/\text{W}$	

**TO-251 (IXTU) Outline**

 1. Gate      2. Drain  
 3. Source    4. Drain

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	2.19	2.38	.086	.094
A1	0.89	1.14	.035	.045
b	0.64	0.89	.025	.035
b1	0.76	1.14	.030	.045
b2	5.21	5.46	.205	.215
c	0.46	0.58	.018	.023
c1	0.46	0.58	.018	.023
D	5.97	6.22	.235	.245
E	6.35	6.73	.250	.265
e	2.28	BSC	.090	BSC
e1	4.57	BSC	.180	BSC
H	17.02	17.78	.670	.700
L	8.89	9.65	.350	.380
L1	1.91	2.28	.075	.090
L2	0.89	1.27	.035	.050

**TO-252 (IXTY) Outline**

 Pins: 1 - Gate      2,4 - Drain  
 3 - Source

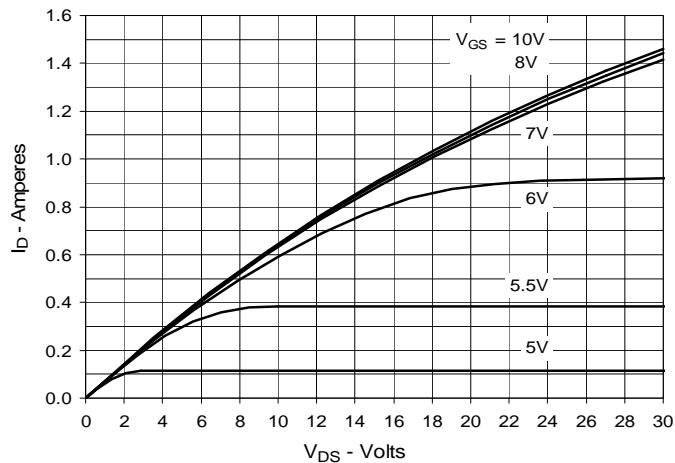
Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	2.19	2.38	0.086	0.094
A1	0.89	1.14	0.035	0.045
A2	0	0.13	0	0.005
b	0.64	0.89	0.025	0.035
b1	0.76	1.14	0.030	0.045
b2	5.21	5.46	.205	.215
c	0.46	0.58	.018	.023
c1	0.46	0.58	.018	.023
D	5.97	6.22	.235	.245
D1	4.32	5.21	.170	.205
E	6.35	6.73	.250	.265
E1	4.32	5.21	.170	.205
e	2.28	BSC	0.090	BSC
e1	4.57	BSC	0.180	BSC
H	9.40	10.42	.370	.410
L	0.51	1.02	.020	.040
L1	0.64	1.02	.025	.040
L2	0.89	1.27	.035	.050
L3	2.54	2.92	.100	.115

 Note 1: Pulse test,  $t \leq 300\mu\text{s}$ ; duty cycle,  $d \leq 2\%$ .

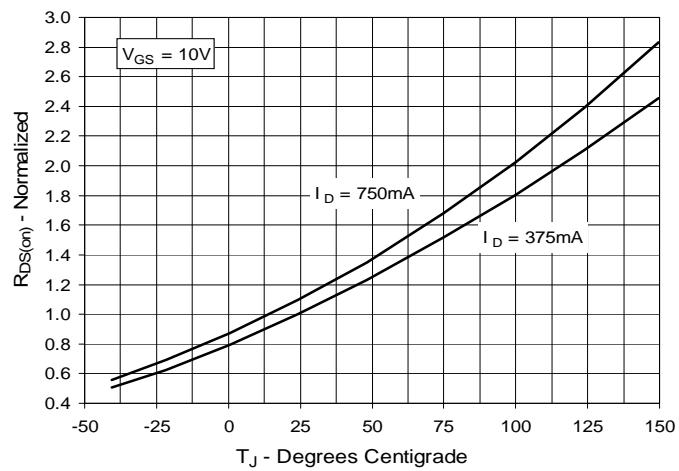
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IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

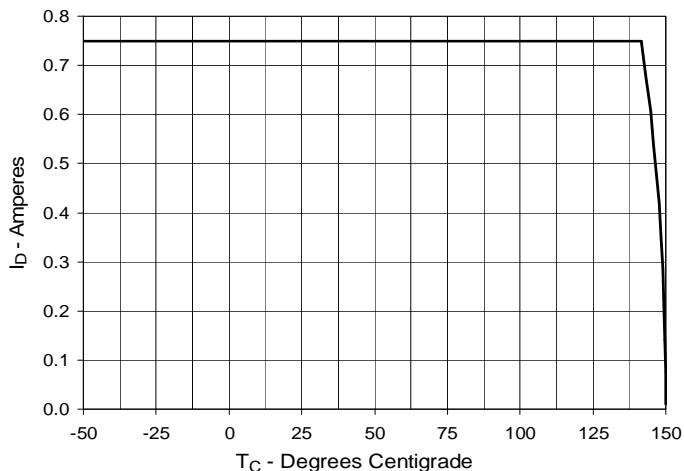
**Fig. 1. Output Characteristics  
@ 25°C**



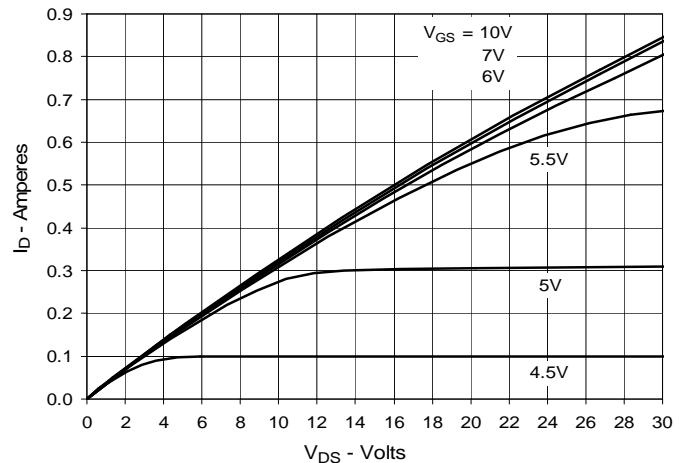
**Fig. 3.  $R_{DS(on)}$  Normalized to  $I_D = 375\text{mA}$   
Value vs. Junction Temperature**



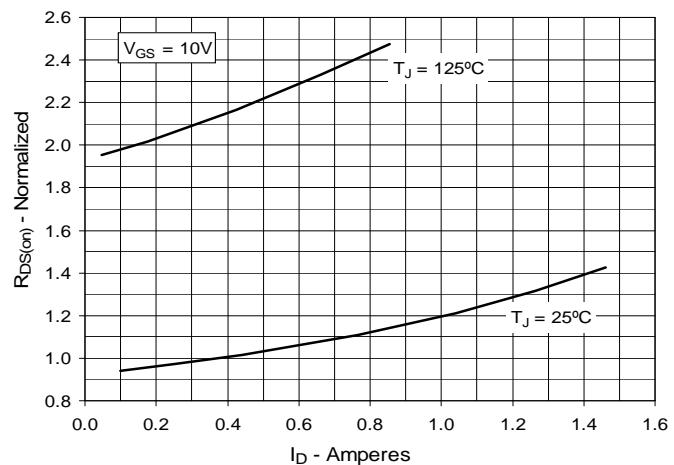
**Fig. 5. Maximum Drain Current vs.  
Case Temperature**



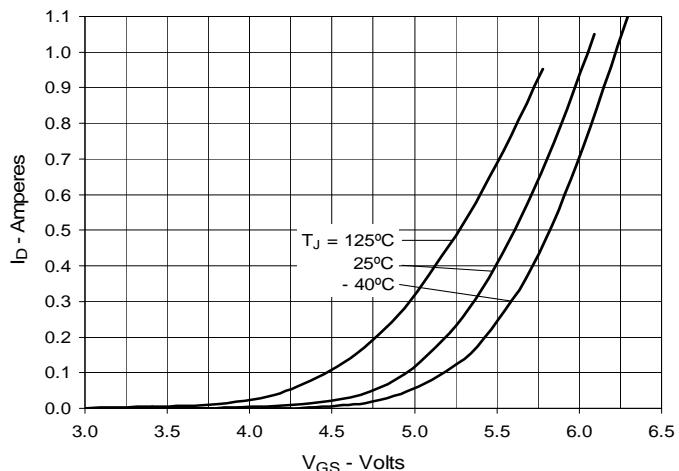
**Fig. 2. Output Characteristics  
@ 125°C**

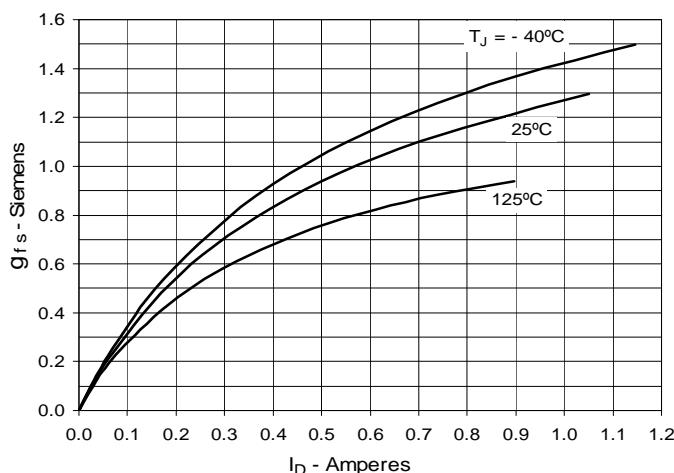
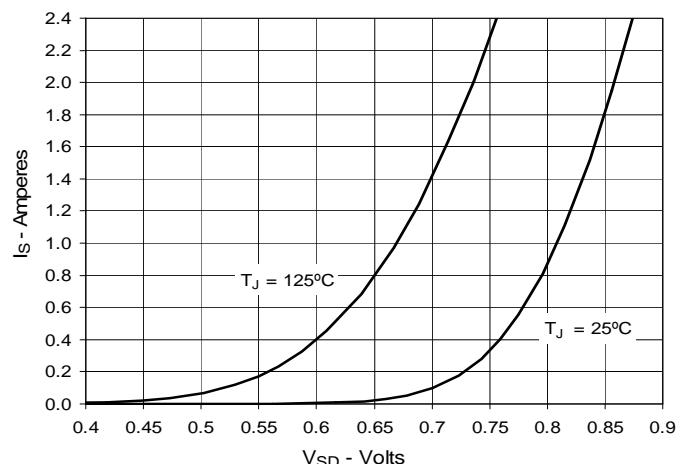
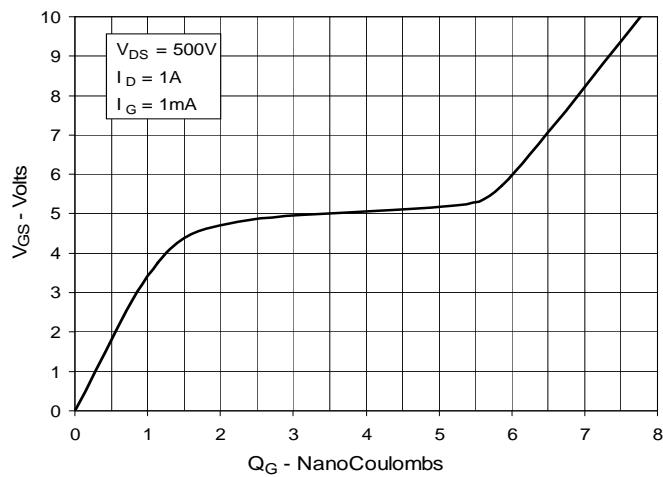
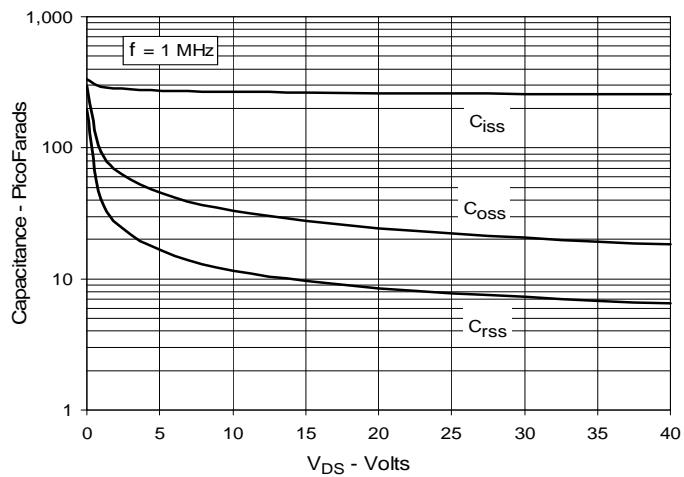
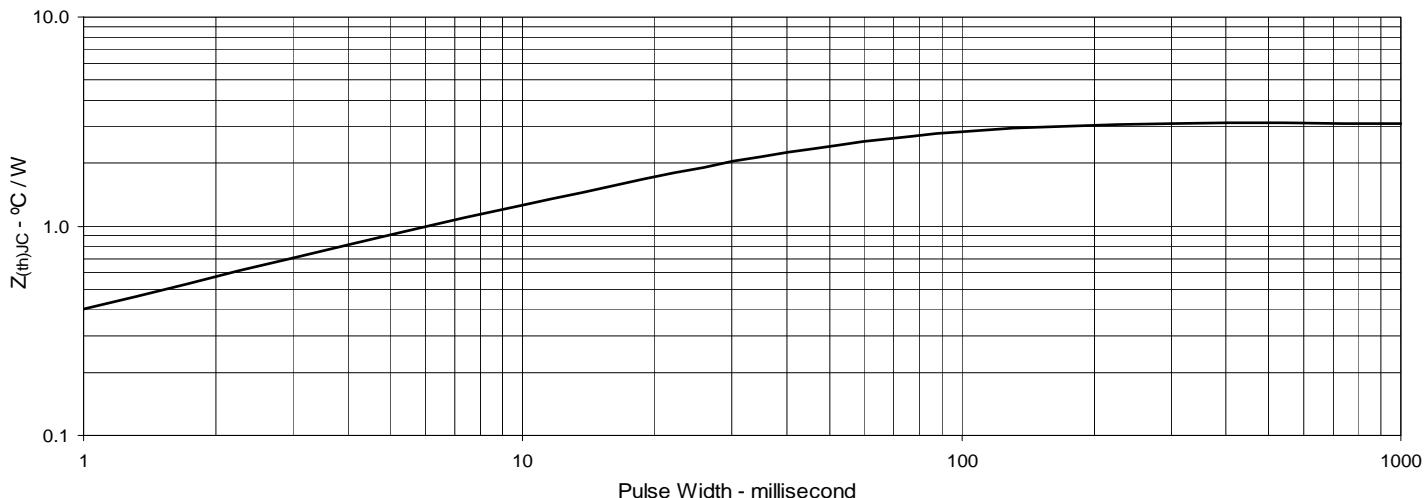


**Fig. 4.  $R_{DS(on)}$  Normalized to  $I_D = 375\text{mA}$   
Value vs. Drain Current**



**Fig. 6. Input Admittance**



**Fig. 7. Transconductance****Fig. 8. Forward Voltage Drop of Intrinsic Diode****Fig. 9. Gate Charge****Fig. 10. Capacitance****Fig. 11. Maximum Transient Thermal Impedance**

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